

Shenzhen Zhongjian Nanfang Testing Co., Ltd.

Report No: CCISE181205401

FCC REPORT

(GSM & WCDMA)

Applicant: Sun Cupid Technology (HK) Ltd.

Address of Applicant: 16/F, CEO Tower, 77 Wing Hong Street, Cheung Sha Wan,

Kowloon, Hong Kong.

Equipment Under Test (EUT)

Product Name: LTE Smart phone

Model No.: N6201L, G4

Trade mark: NUU

FCC ID: 2ADINN6201L

FCC CFR Title 47 Part 2

Applicable standards: FCC CFR Title 47 Part 22 Subpart H

FCC CFR Title 47 Part 24 Subpart E

FCC CFR Title 47 Part 27 Subpart L

Date of sample receipt: 14 Dec., 2018

Date of Test: 14 Dec., to 22 Dec., 2018

Date of report issued: 25 Dec., 2018

Test Result: PASS*

* In the configuration tested, the EUT complied with the standards specified above.

Authorized Signature:



Bruce Zhang Laboratory Manager

This report details the results of the testing carried out on one sample. The results contained in this test report do not relate to other samples of the same product and does not permit the use of the CCIS product certification mark. The manufacturer should ensure that all products in series production are in conformity with the product sample detailed in this report.

This report may only be reproduced and distributed in full. If the product in this report is used in any configuration other than that detailed in the report, the manufacturer must ensure the new system complies with all relevant standards.

This document cannot be reproduced except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested and such sample(s) are retained for 90 days only.





2. Version

Version No.	Date	Description
00	25 Dec., 2018	Original

Tested by: Query (her Date: 25 Dec., 2018

Test Engineer

Reviewed by: 25 Dec., 2018

Project Engineer



3. Contents

			Page
1.	CO	VER PAGE	1
2.	VE	RSION	2
3.		ONTENTS	
4.		ST SUMMARY	
5.		NERAL INFORMATION	
	5.1	CLIENT INFORMATION	
	5.1 5.2	GENERAL DESCRIPTION OF E.U.T.	
	5.3	TEST MODES	
	5.4	DESCRIPTION OF SUPPORT UNITS	
	5.5	MEASUREMENT UNCERTAINTY	
	5.6	LABORATORY FACILITY	
	5.7	LABORATORY LOCATION	8
	5.8	TEST INSTRUMENTS LIST	8
6.	TES	ST RESULTS	9
	6.1	CONDUCTED OUTPUT POWER, ERP AND EIRP	9
	6.2	PEAK-TO-AVERAGE POWER RATIO	
	6.3	OCCUPY BANDWIDTH	16
	6.4	MODULATION CHARACTERISTIC	
	6.5	OUT OF BAND EMISSION AT ANTENNA TERMINALS	
	6.6	FIELD STRENGTH OF SPURIOUS RADIATION MEASUREMENT	
	6.7	FREQUENCY STABILITY V.S. TEMPERATURE MEASUREMENT	
	6.8	FREQUENCY STABILITY V.S. VOLTAGE MEASUREMENT	45
7	TES	ST SETUP PHOTO	48
R	FU	T CONSTRUCTIONAL DETAILS	49





4. Test Summary

Test Item	Section in CFR 47	Result
RF Exposure (SAR)	Part 1.1307 Part 2.1093	Pass (Please refer to SAR Report)
RF Output Power	Part 2.1046 Part 22.913 (a)(2) Part 24.232 (c) Part 27.50 (d)(4)	Pass
Peak-to-Average Power Ratio	Part 24.232 (d) Part 27.50(d)(5)	Pass
Modulation Characteristics	Part 2.1047	Pass
99% & -26 dB Occupied Bandwidth	Part 2.1049 Part 22.917(b) Part 24.238(b) Part 27.53(h)	Pass
Out of band emission at antenna terminals	Part 2.1053 Part 22.917 (a) Part 24.238 (a) Part 27.53 (h)	Pass
Field strength of spurious radiation	Part 22.917 (a) Part 24.238 (a) Part 27.53 (h)	Pass
Frequency stability vs. temperature	Part 22.355 Part 24.235 Part 27.54 Part 2.1055(a)(1)(b)	Pass
Frequency stability vs. voltage	Part 22.355 Part 24.235 Part 27.54 Part 2.1055(d)(2)	Pass



5. General Information

5.1 Client Information

Applicant:	Sun Cupid Technology (HK) Ltd.
Address:	16/F, CEO Tower, 77 Wing Hong Street, Cheung Sha Wan, Kowloon, Hong Kong.
Manufacturer	Sun Cupid Technology (HK) Ltd.
Address:	16/F, CEO Tower, 77 Wing Hong Street, Cheung Sha Wan, Kowloon, Hong Kong.
Factory:	SUNCUPID (ShenZhen) Electronic Ltd
Address:	Baolong Industrial City, Longgang District, Shenzhen Hi-Tech Road, Building 1, A 7, China.

5.2 General Description of E.U.T.

0.2 Ochiciai Description	<u> </u>
Product Name:	LTE Smart phone
Model No.:	N6201L, G4
Operation Frequency range:	GSM 850: 824.20MHz-848.80MHz
	PCS1900: 1850.20MHz-1909.80MHz
	WCDMA Band V: 826.4MHz-846.6MHz
	WCDMA Band II: 1852.4 MHz-1907.6 MHz
	WCDMA Band IV: 1712.4 MHz-1752.6 MHz
Modulation type:	GSM/GPRS: GMSK, UMTS: QPSK, EGPRS: 8PSK
Antenna type:	Internal Antenna
Antenna gain:	GSM 850: -1.53 dBi
	PCS 1900: 0.11 dBi
	WCDMA Band V: -0.12 dBi
	WCDMA Band II: 0.12 dBi
	WCDMA Band IV: 0.50 dBi
Power supply:	Rechargeable Li-ion Battery DC 3.85V, 3750mAh
AC adapter:	Model: HJ-FC001K7-US
	Input: AC100-240V, 50/60Hz, 0.6A
	Output: DC 5.0V, 2000mA / DC 9.0V, 2000mA
Test Sample Condition:	The test samples were provided in good working order with no visible defects.
Remark:	N6201L, G4 were identical inside, the electrical circuit design, layout, components used and internal wiring, with only difference being model name and for different areas, They all have two memory configurations, 1:6G(RAM) + 64G(ROM); 2: 6G(RAM) + 128G(ROM).



Operation Frequency List:

GSN	1 850	PCS1900		
Channel Frequency (MHz)		Channel	Frequency (MHz)	
128	824.20	512	1850.20	
129			1850.40	
		513		
189	836.40	660	1879.80	
	836.60		1	
190		661	1880.00	
191	836.80	662	1880.20	
250	848.60	809	1909.60	
251	848.80	810	1909.80	
	A Band V		IA Band II	
Channel	Frequency (MHz)	Channel	Frequency (MHz)	
4132	826.40	9262	1852.40	
4133	826.60	9263	1852.60	
4182	836.40	9399	1879.80	
4183	836.60	9400	1880.00	
4184	836.80	9401	1880.20	
4232			1907.40	
4233	846.60	9538	1907.60	
WCDMA	Band IV			
Channel	Frequency (MHz)			
1312	1712.40			
1313	1712.60			
1412 1732.40				
1413				
1414				
1512	1752.40			
1513	1752.60			

Regards to the operating frequency range over 10 MHz, the Lowest frequency, the middle frequency, and the highest frequency of channel were selected to perform the test, and the selected channel see below:

GSM850			PCS1900		
Channel		Frequency(MHz)	Channel		Frequency(MHz)
Lowest channel	128	824.20	Lowest channel	512	1850.20
Middle channel	190	836.60	Middle channel	661	1880.00
Highest channel	251	848.80	Highest channel	810	1909.80
1	WCDMA Band V	1	,	WCDMA Band I	
Chann	Channel		Channel		Frequency(MHz)
Lowest channel	4132	826.40	Lowest channel	9262	1852.40
Middle channel	4183	836.60	Middle channel	9400	1880.00
Highest channel	4233	846.60	Highest channel	9538	1907.60
V	VCDMA Band IV	/			
Channel		Frequency(MHz)			
Lowest channel	Lowest channel 1312				
Middle channel 1413		1732.60			
Highest channel 1513		1752.60			



5.3 Test modes

Operating Environmen	Operating Environment:			
Temperature:	Normal: 15℃ ~ 35℃, Extreme: -30℃ ~ +50℃			
Humidity:	20 % ~ 75 % RH			
Atmospheric Pressure:	1008 mbar			
Voltage:	Nominal: 3.85Vdc, Extreme: Low 3.5 Vdc, High 4.40 Vdc			
Test mode:				
GSM mode	Keep the EUT communication with simulated station in GSM mode			
GPRS mode	Keep the EUT communication with simulated station in GPRS mode			
EGPRS mode	Keep the EUT communication with simulated station in EGPRS mode			
RMC mode	Keep the EUT communication with simulated station in RMC mode			
HSDPA	Keep the EUT communication with simulated station in HSDPA mode			
HSUPA	Keep the EUT communication with simulated station in HSUPA mode			

Remark: The EUT has been tested under continuous transmitting mode. Channel Low, Mid and High for each type band with rated data rate were chosen for full testing. The field strength of spurious radiation emission was measured as EUT stand-up position (H mode) and lie down position (E1, E2 mode) for these modes with power adaptor, earphone and Data cable. Just the worst case position (H mode) shown in report.

5.4 Description of Support Units

Test Equipment	Manufacturer	Model No.	Serial No.	
Simulated Station	Anritsu	MT8820C	6201026545	

5.5 Measurement Uncertainty

Parameters	Expanded Uncertainty
Radiated Emission (9kHz ~ 30MHz)	±2.76 dB (k=2)
Radiated Emission (30MHz ~ 1000MHz)	±4.28 dB (k=2)
Radiated Emission (1GHz ~ 18GHz)	±5.72 dB (k=2)
Radiated Emission (18GHz ~ 40GHz)	±2.88 dB (k=2)

5.6 Laboratory Facility

The test facility is recognized, certified, or accredited by the following organizations:

• FCC - Registration No.: 727551

Shenzhen Zhongjian Nanfang Testing Co., Ltd. has been accredited as a testing laboratory by FCC (Federal Communications Commission). The Registration No. is 727551.

IC - Registration No.: 10106A-1

The 3m Semi-anechoic chamber of Shenzhen Zhongjian Nanfang Testing Co., Ltd. has been Registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 10106A-1.

CNAS - Registration No.: CNAS L6048

Shenzhen Zhongjian Nanfang Testing Co., Ltd. is accredited to ISO/IEC 17025:2005 General Requirements for the Competence of Testing and Calibration laboratories for the competence of testing. The Registration No. is CNAS L6048.

A2LA - Registration No.: 4346.01

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005 General requirements for the competence of testing and calibration laboratories. The test scope can be found as below link: https://portal.a2la.org/scopepdf/4346-01.pdf



5.7 Laboratory Location

Shenzhen Zhongjian Nanfang Testing Co., Ltd.

Address: No. B-C, 1/F., Building 2, Laodong No.2 Industrial Park, Xixiang Road,

Bao'an District, Shenzhen, Guangdong, China Tel: +86-755-23118282, Fax: +86-755-23116366

Email: info@ccis-cb.com, Website: http://www.ccis-cb.com

5.8 Test Instruments list

Test Equipment	Manufacturer	Model No.	Serial No.	Cal. Date (mm-dd-yy)	Cal. Due date (mm-dd-yy)
3m SAC	SAEMC	9m*6m*6m	966	07-22-2017	07-21-2020
BiConiLog Antenna	SCHWARZBECK	VULB9163	497	03-16-2018	03-15-2019
Biconical Antenna	SCHWARZBECK	VUBA9117	359	06-22-2017	06-21-2020
Horn Antenna	SCHWARZBECK	BBHA9120D	916	03-16-2018	03-15-2019
Horn Antenna	SCHWARZBECK	BBHA9120D	1805	06-22-2017	06-21-2020
Horn Antenna	SCHWARZBECK	BBHA 9170	BBHA9170582	11-21-2018	11-20-2019
EMI Test Software	AUDIX	E3	V	ersion: 6.110919b	
Pre-amplifier	HP	8447D	2944A09358	03-07-2018	03-06-2019
Pre-amplifier	CD	PAP-1G18	11804	03-07-2018	03-06-2019
Spectrum analyzer	Rohde & Schwarz	FSP30	101454	03-07-2018	03-06-2019
Spectrum analyzer	Rohde & Schwarz	FSP40	100363	11-21-2018	11-20-2019
EMI Test Receiver	Rohde & Schwarz	ESRP7	101070	03-07-2018	03-06-2019
Spectrum Analyzer	Agilent	N9020A	MY50510123	11-10-2018	11-09-2019
Signal Generator	Rohde & Schwarz	SMX	835454/016	03-07-2018	03-06-2019
Signal Generator	R&S	SMR20	1008100050	03-07-2018	03-06-2019
RF Switch Unit	MWRFTEST	MW200	N/A	N/A	N/A
Test Software	MWRFTEST	MTS8200		Version: 2.0.0.0	
Cable	ZDECL	Z108-NJ-NJ-81	1608458	03-07-2018	03-06-2019
Cable	MICRO-COAX	MFR64639	K10742-5	03-07-2018	03-06-2019
Cable	SUHNER	SUCOFLEX100	58193/4PE	03-07-2018	03-06-2019
DC Power Supply	XinNuoEr	WYK-10020K	1409050110020	10-31-2018	10-30-2019
Temperature Humidity Chamber	HengPu	HPGDS-500	20140828008	09-24-2018	09-23-2019
Simulated Station	Rohde & Schwarz	CMW500	140493	07-16-2018	07-15-2019



6. Test results

6.1 Conducted Output Power, ERP and EIRP

Test Requirement:	FCC part 22.913(a)(2), FCC part 24.232(c), FCC part 27.50(d)(4)		
Test Method:	ANSI/TIA-603-D 2010		
Limit:	GSM 850: 7W, PCS 1900: 2W WCDMA Band V: 7W, WCDMA Band II: 2W, WCDMA Band IV: 1W		
Test setup:	System simulator ATT EUT		
Test Procedure:	The transmitter output was connected to a calibrated attenuator, the other end of which was connected to the simulated station. Transmitter output power was read off in dBm.		
Test Instruments:	Refer to section 5.8 for details		
Test mode:	Refer to section 5.3 for details		
Test results:	Passed		



Measurement Data:

	Bu	Burst Average power (dBm)		
EUT Mode	128	190	251	
	824.20 (MHz)	836.60 (MHz)	848.80 (MHz)	
GSM 850	32.04	33.05	33.04	
GPRS 850 (1 Uplink slot)	32.94	32.93	32.96	
GPRS 850 (2 Uplink slot)	32.16	32.18	32.2	
GPRS 850 (3 Uplink slot)	30.26	30.31	30.36	
GPRS 850 (4 Uplink slot)	29.00	29.07	29.12	
Antenna Gain (dBi)		-1.53		
Max. ERP (dBm)		29.37		
ERP Limit (dBm)		38.45		
EGPRS 850 (1 Uplink slot)	27.46	27.39	27.45	
EGPRS 850 (2 Uplink slot)	26.07	26.10	26.11	
EGPRS 850 (3 Uplink slot)	23.79	23.71	23.82	
EGPRS 850 (4 Uplink slot)	22.40	22.33	22.42	
Antenna Gain (dBi)	-1.53			
Max. ERP (dBm)	23.78			
ERP Limit (dBm)	38.45			

	Bu	ırst Average power (dB	m)	
EUT Mode	512	661	810	
	1850.20 (MHz)	1880.00 (MHz)	1909.80 (MHz)	
PCS 1900	29.79	29.81	29.85	
GPRS 1900 (1 Uplink slot)	29.72	29.74	29.79	
GPRS 1900 (2 Uplink slot)	28.87	28.9	28.98	
GPRS 1900 (3 Uplink slot)	26.85	26.91	27.01	
GPRS 1900 (4 Uplink slot)	25.76	25.82	25.92	
Antenna Gain (dBi)		0.11		
Max. EIRP (dBm)		29.96		
EIRP Limit (dBm)		33.00		
EGPRS 1900 (1 Uplink slot)	25.99	25.92	25.82	
EGPRS 1900 (2 Uplink slot)	24.71	24.62	24.59	
EGPRS 1900 (3 Uplink slot)	22.67	22.58	22.42	
EGPRS 1900 (4 Uplink slot)	21.33	21.2	21.08	
Antenna Gain (dBi)		0.11		
Max. EIRP (dBm)	26.10			
EIRP Limit (dBm)	33.00			
N (5155 (15) 5 (4 (15) 4 (15)				

Note: EIRP(dBm) = Burst Average power(dBm) + Antenna Gain(dBi). ERP(dBm) = EIRP(dBm) - 2.15(dB).



		Bur	st Average power (dl	3m)
EUT Mode		4132	4183	4233
		826.40 (MHz)	836.60 (MHz)	846.60 (MHz)
	Subtest 1	22.82	22.84	22.87
UMTS 850	Subtest 2	22.48	22.43	22.48
HSDPA	Subtest 3	20.93	20.91	20.91
	Subtest 4	20.86	20.85	20.95
	Subtest 1	22.33	22.35	22.38
LIMTO OFO	Subtest 2	22.79	22.79	22.82
UMTS 850	Subtest 3	20.37	20.36	20.34
HSUPA	Subtest 4	22.86	22.81	22.89
	Subtest 5	21.40	21.29	21.34
UMTS 850 RMC	12.2kbps	23.91	23.89	23.91
UMTS 850 AMR	12.2kbps	23.82	23.79	23.69
Antenna Gain (dBi)			-0.12	
Max. ERP (dBm)		21.64		
ERP Limit (dBm)		38.45		

		Bur	st Average power (di	3m)
CUT Mada		9262	9400	9538
EUT Mode		1852.40	1880.00	1907.60
		(MHz)	(MHz)	(MHz)
	Subtest 1	22.19	22.07	22.06
UMTS 1900	Subtest 2	21.71	21.71	21.68
HSDPA	Subtest 3	20.14	20.20	20.11
	Subtest 4	20.15	20.06	20.01
	Subtest 1	21.63	21.67	21.56
LIMTO 4000	Subtest 2	22.03	22.01	22.01
UMTS 1900	Subtest 3	19.74	19.75	19.60
HSUPA	Subtest 4	22.06	22.01	21.96
	Subtest 5	20.61	20.64	20.49
UMTS 1900 RMC	12.2kbps	23.14	23.15	23.21
UMTS 1900 AMR	12.2kbps	23.06	23.02	23.03
Antenna Gain (dBi)		0.12		
Max. EIRP (dBm)		23.33		
EIRP Limit (dBm)		33.00		
N : FIRR (IR) R : A	(15.) 4 : 6 : (15.)	•		

Note: EIRP(dBm) = Burst Average power(dBm) + Antenna Gain(dBi). ERP(dBm) = EIRP(dBm) - 2.15(dB).



		Bur	st Average power (dl	Bm)
EUT Mode		1312	1412	1513
		1712.40 (MHz)	1732.40 (MHz)	1752.60 (MHz)
	Subtest 1	21.93	22.03	21.9
UMTS 1700	Subtest 2	21.61	21.61	21.6
HSDPA	Subtest 3	20.21	20.09	19.96
	Subtest 4	20.23	20.26	20.08
	Subtest 1	21.72	21.68	21.57
LIMTO 4700	Subtest 2	22.04	22	21.99
UMTS 1700	Subtest 3	19.79	19.81	19.61
HSUPA	Subtest 4	22.04	22.04	22.02
	Subtest 5	20.64	20.63	20.61
UMTS 1700 RMC	12.2kbps	23.14	23.11	22.96
UMTS 1700 AMR	12.2kbps	23.01	22.98	22.82
Antenna Gain (dBi)		0.50	
Max. EIRP (dBm)		23.57		
EIRP Limit (dBm)		30.00		
Note: EIRP (dBm) = Burst Average power	(dBm) + Antenna Gain (dBi)		_	



6.2 Peak-to-Average Power Ratio

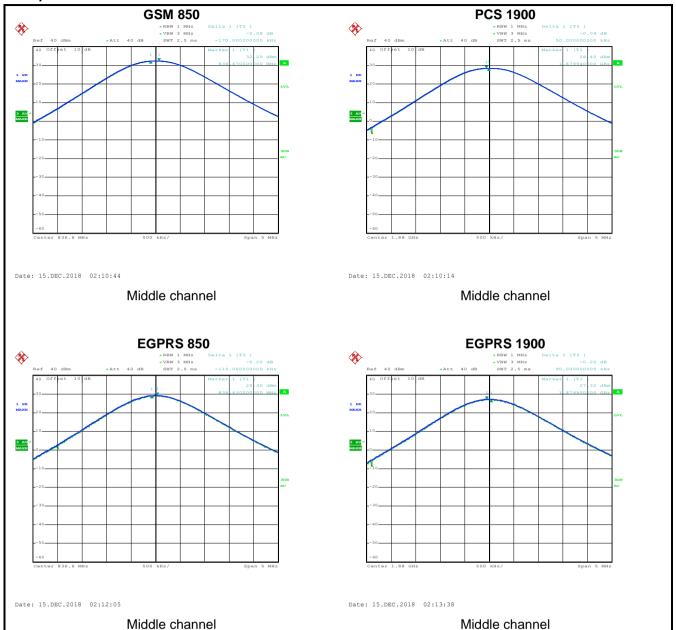
Test Requirement:	FCC part 24.232(d), FCC part 27.50(d)(5)
Test Method	ANSI/TIA-603-D 2010
Limit:	The peak-to-average ratio (PAR) of the transmission may not exceed 13 dB.
Test setup:	System simulator Spectrum Analyzer
Test Procedure:	 The RF output of the transceiver was connected to a spectrum analyzer through appropriate attenuation. Set the CCDF option in spectrum analyzer, RBW ≥ OBW, Set the EUT working in highest power level, measured and recorded the 0.1% as PAPR level. Repeat step 1~3 at other frequency and modulations.
Test Instruments:	Refer to section 5.8 for details
Test mode:	Refer to section 5.3 for details
Test results:	Passed

Measurement Data:

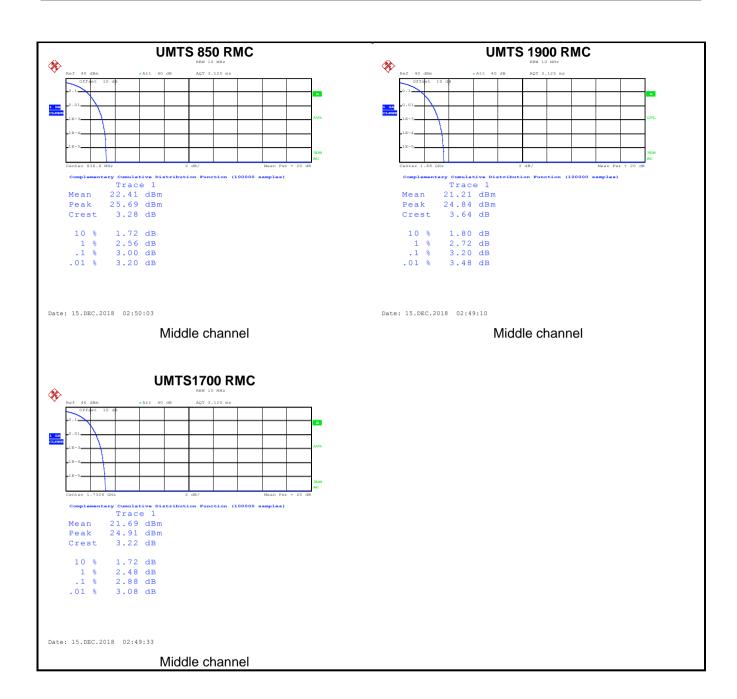
Modulation	Test channel	PAPR
GSM 850	190	-0.08
EGPRS 850	190	-0.09
PCS 1900	661	-0.20
EGPRS 1900	661	-0.20
UMTS 850 RMC	4183	3.00
UMTS 1900 RMC	9400	3.20
UMTS1700 RMC	1413	2.88



Test plots as below:









6.3 Occupy Bandwidth

Test Requirement:	FCC part 22.917(b), FCC part 24.238(b), FCC Part 27.53(h)
Test Method:	ANSI/TIA-603-D 2010
Test setup:	System simulator Splitter ATT EUT Spectrum Analyzer
Test Procedure:	 The EUT's output RF connector was connected with a short cable to the spectrum analyzer RBW was set to about 1% of emission BW, VBW= 3 times RBW. -26dBc display line was placed on the screen (or 99% bandwidth), the occupied bandwidth is the delta frequency between the two points where the display line intersects the signal trace.
Test Instruments:	Refer to section 5.8 for details
Test mode:	Refer to section 5.3 for details
Test results:	Passed





Measurement Data:

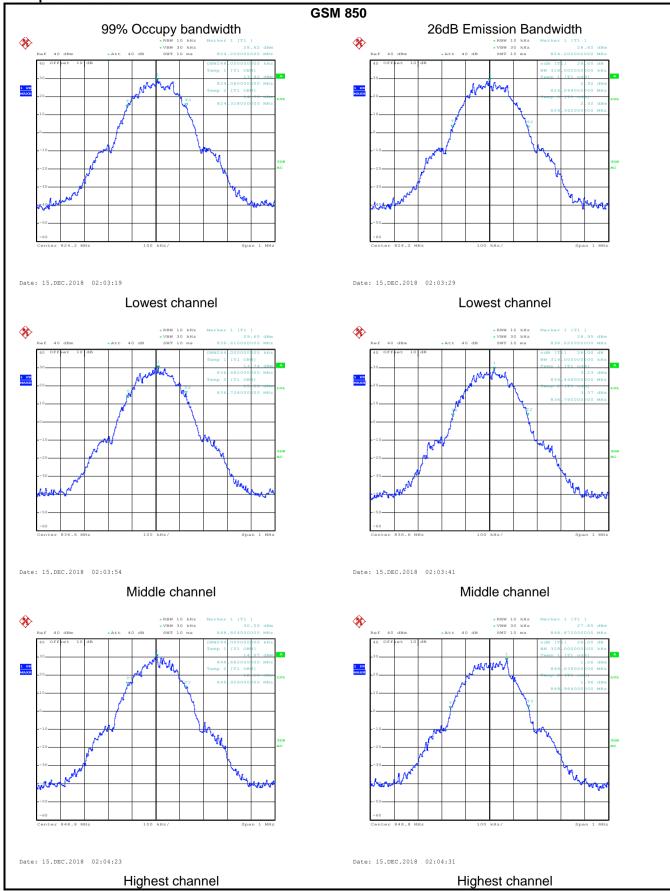
EUT Mode	Channel	Frequency (MHz)	99% Occupy bandwidth (kHz)	-26dB bandwidth (kHz)
	128	824.2	248	318
GSM 850	190	836.6	244	314
	251	848.8	244	328
	128	824.2	246	312
EGPRS850	190	836.6	244	316
	251	848.8	250	312
	512	1850.2	242	320
PCS 1900	661	1880.0	250	318
	810	1909.8	246	318
	512	1850.2	250	318
EGPRS1900	661	1880.0	248	318
	810	1909.8	250	314
LINATO 050	4132	826.4	4180	4740
UMTS 850 12.2k RMC	4183	836.6	4180	4720
12.2K KIVIC	4233	846.6	4180	4700
	9262	1852.4	4180	4680
UMTS 1900 12.2k RMC	9400	1880.0	4200	4720
12.2K KIVIC	9538	1907.6	4180	4720
	1312	1712.40	4180	4720
UMTS 1700 12.2k RMC	1413	1732.60	4180	4720
IZ.ZK KIVIC	1513	1752.60	4180	4740

Note:

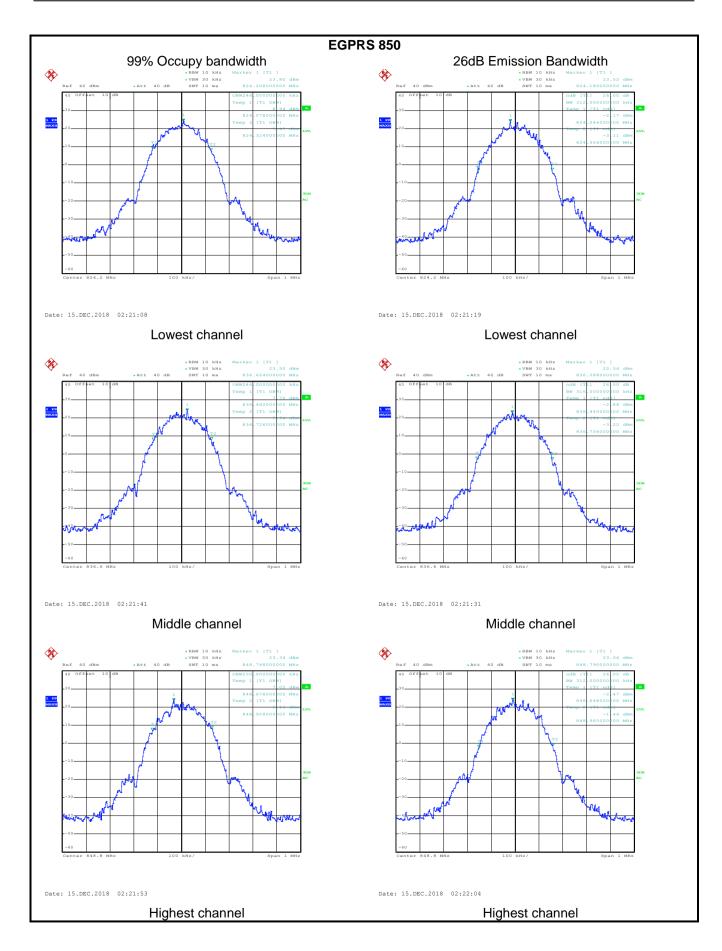
GSM & GPRS use the same modulation technical (GMSK), and with the same channels, so the 99% OBW and the -26dB of GPRS not performed.



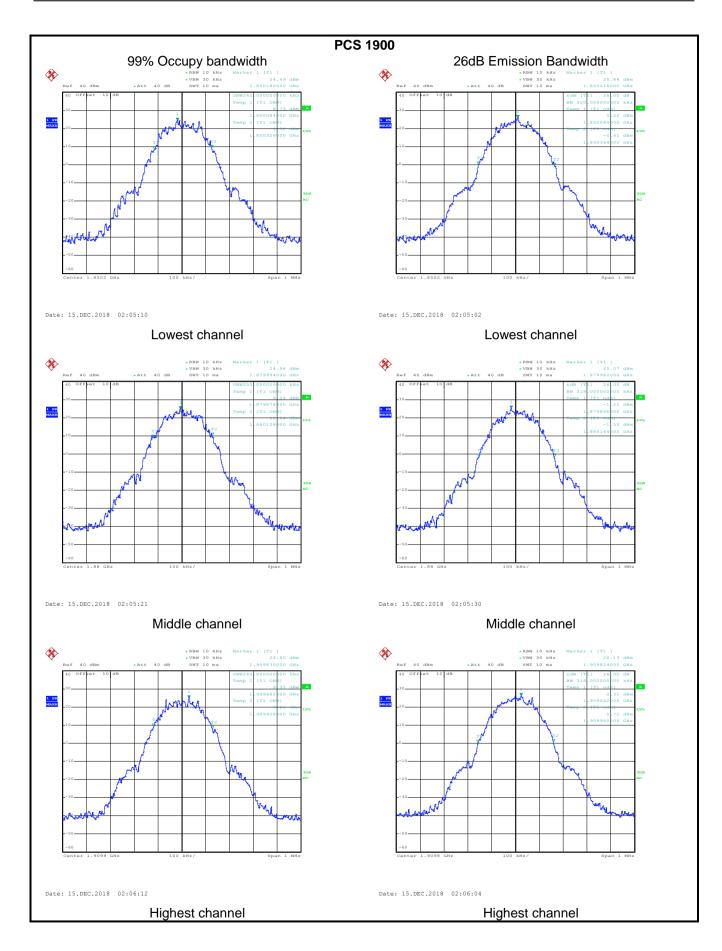
Test plot as follows:



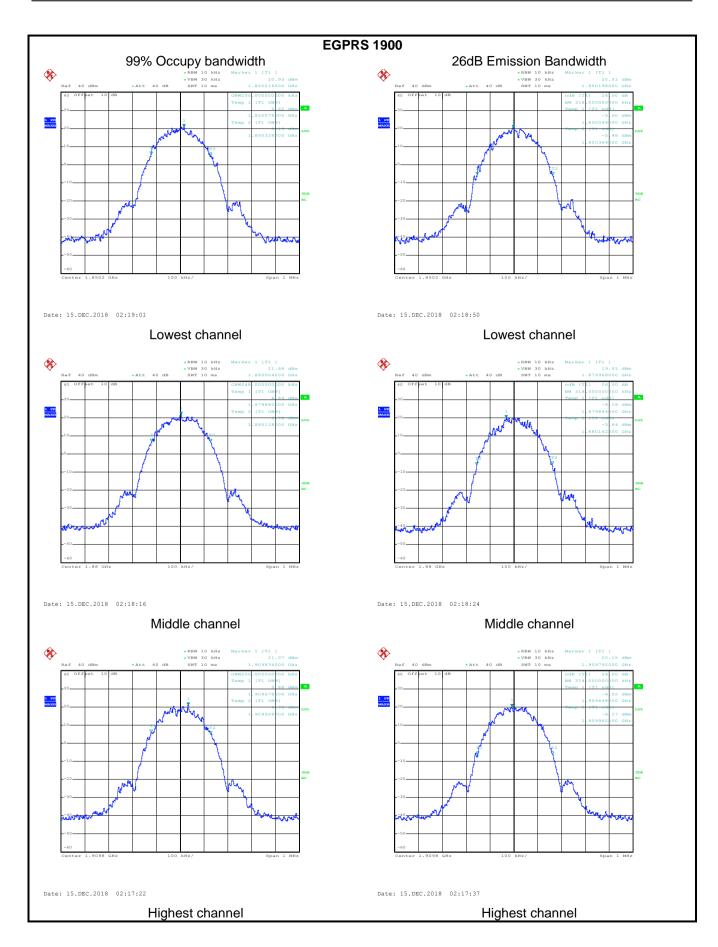




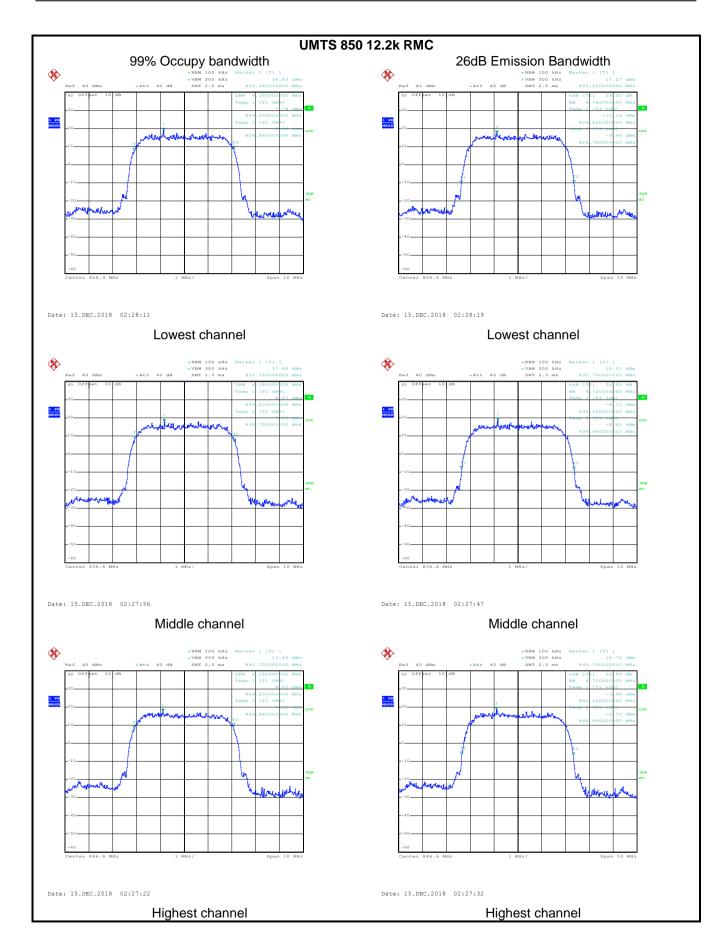




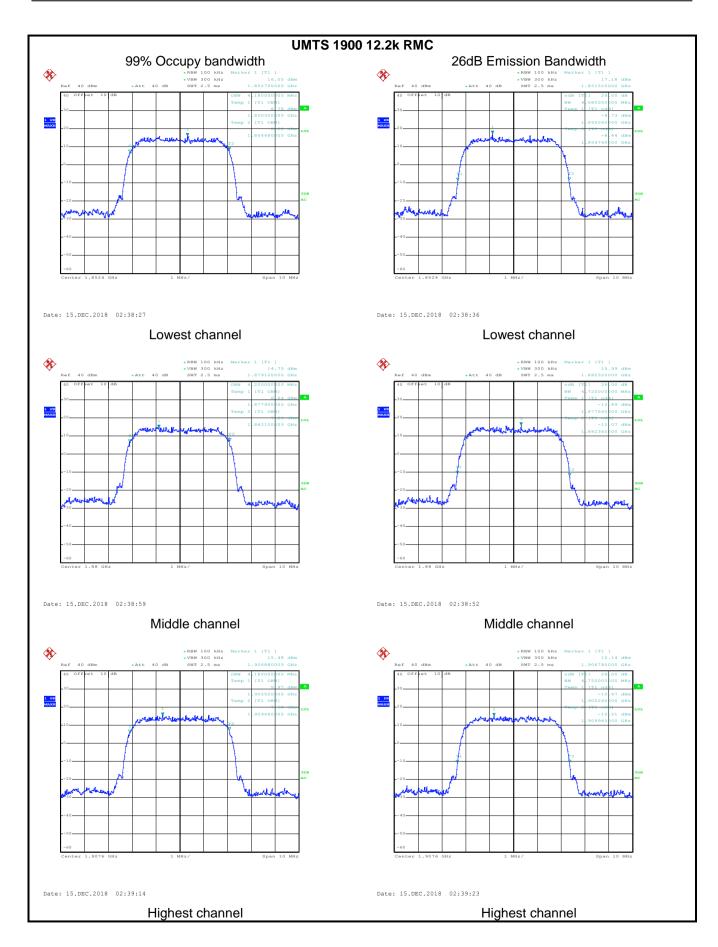




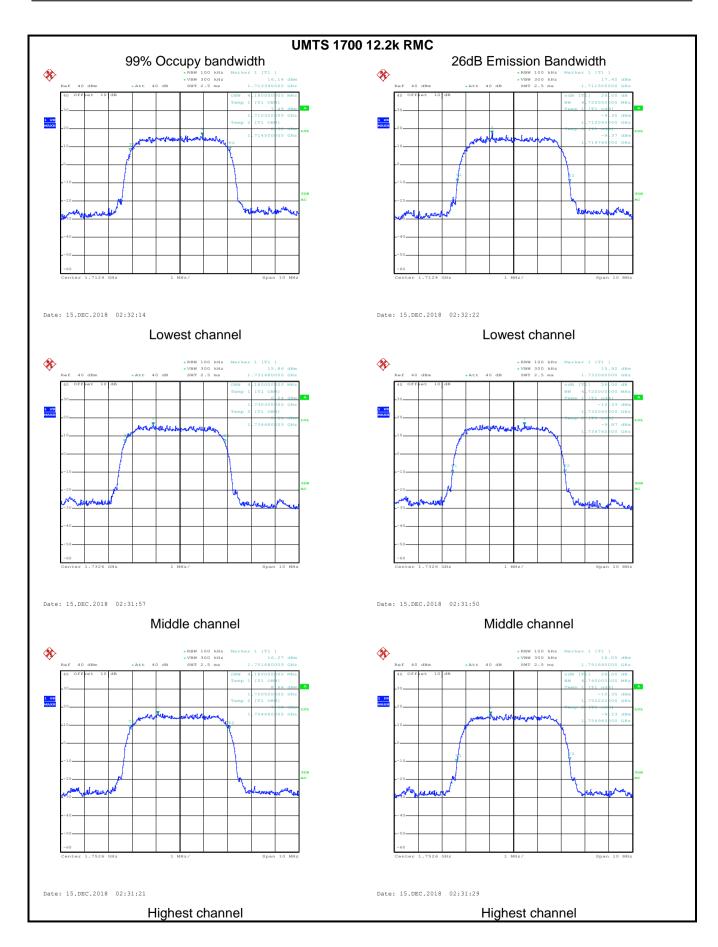














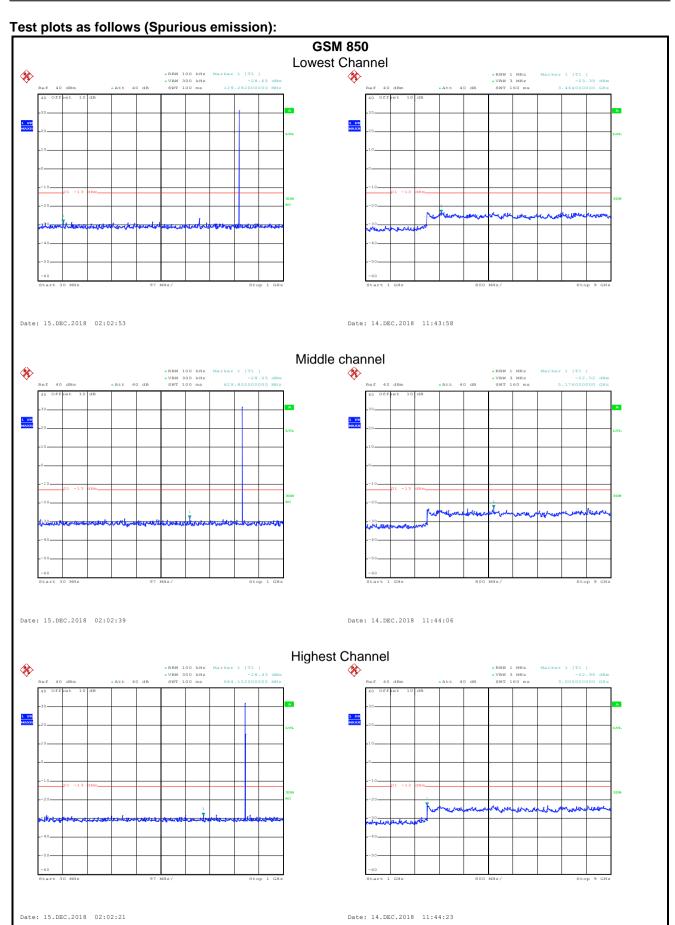
6.4 Modulation Characteristic

According to FCC § 2.1047(d), Part 22H & 24E & 27L there is no specific requirement for digital modulation, therefore modulation characteristic is not presented.

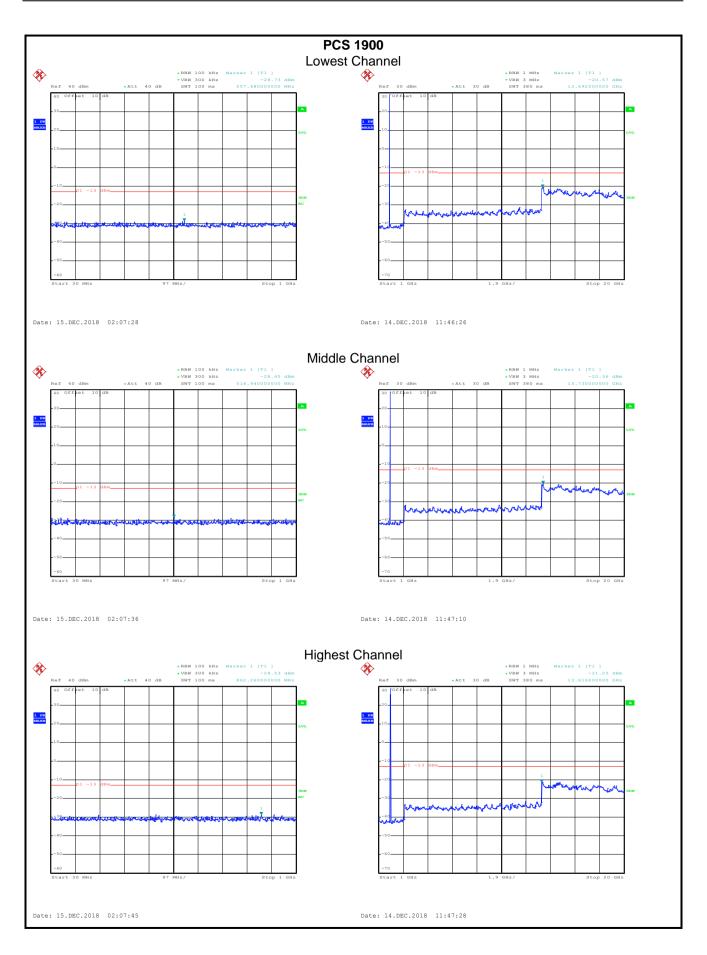
6.5 Out of band emission at antenna terminals

Test Requirement:	FCC part 22.917(a), FCC part 24.238(a), FCC Part 27.53 (h)
Test Method:	ANSI/TIA-603-D 2010
Limit:	-13dBm
Test setup:	System simulator Spectrum Analyzer Spectrum Analyzer
Test Procedure:	 The RF output of the transceiver was connected to a spectrum analyzer through appropriate attenuation. The resolution bandwidth of the spectrum analyzer was set at 100 kHz when below 1GHz, 1MHz when above 1 GHz; sufficient scans were taken to show the out of band Emissions if any up to 10th harmonic. For the out of band: Set the RBW=100 kHz, VBW=300 kHz when below 1 GHz, RBW =1 MHz, VBW=3 MHz when above 1 GHz, Start=30MHz, Stop= 10th harmonic. Band Edge Requirements: In the 1 MHz bands immediately outside and adjacent to the frequency block, a resolution bandwidth of at least 1 percent of the emission bandwidth of the fundamental emission of the transmitter may be employed to measure the out of band Emissions.
Test Instruments:	Refer to section 5.8 for details
Test mode:	Refer to section 5.3 for details
Test results:	Passed

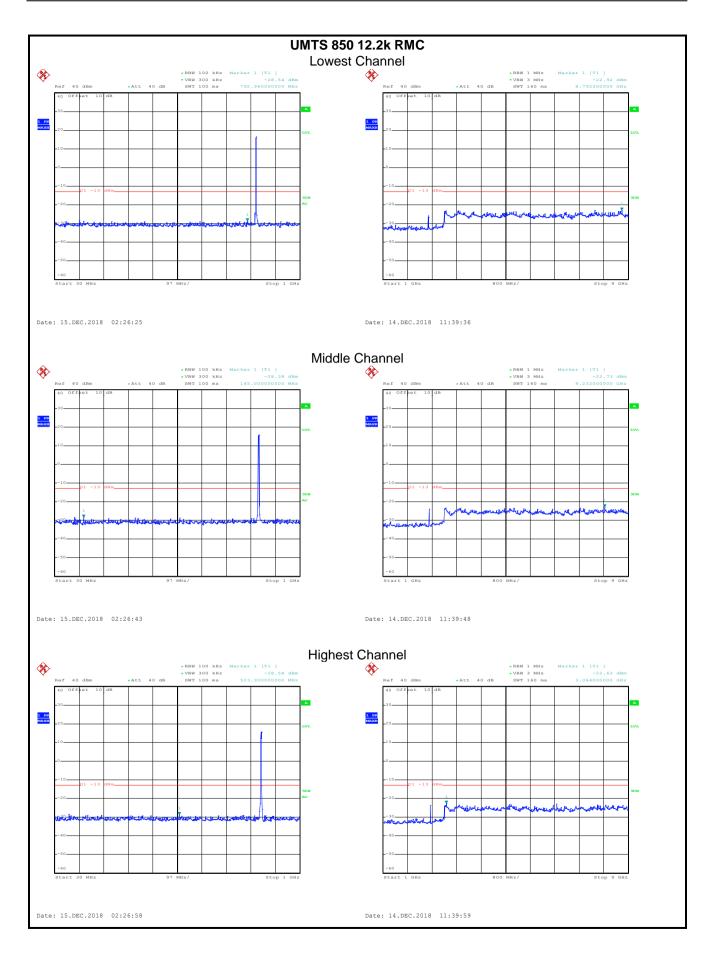




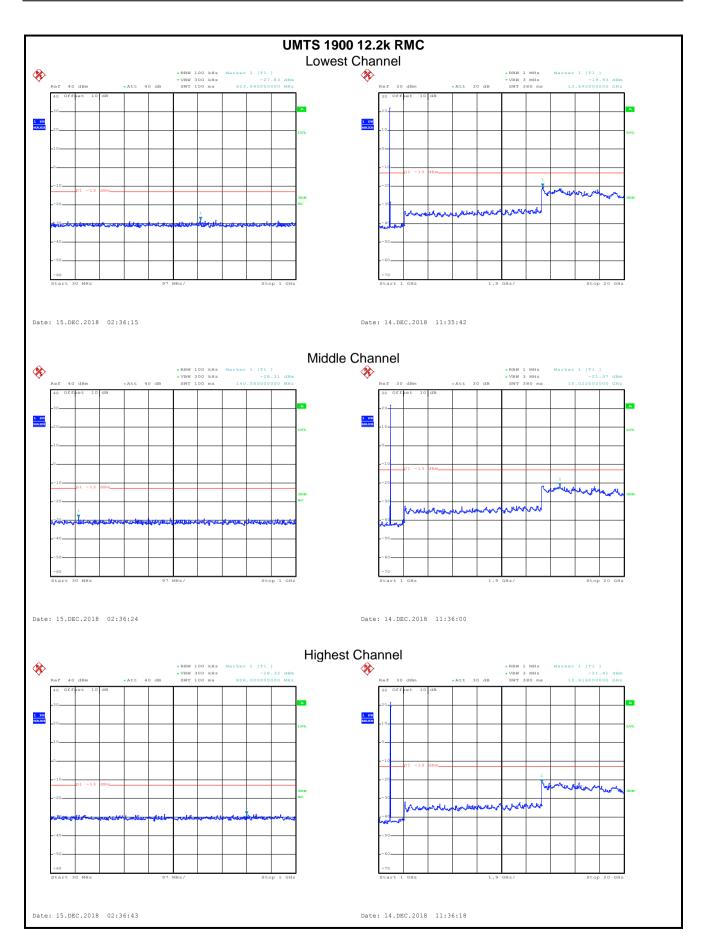




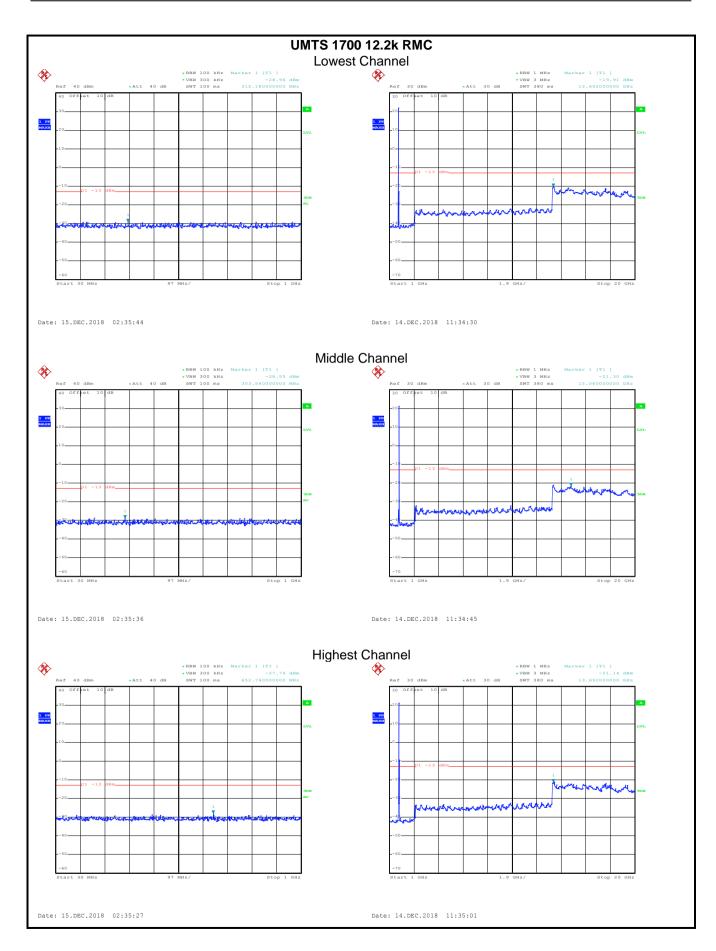






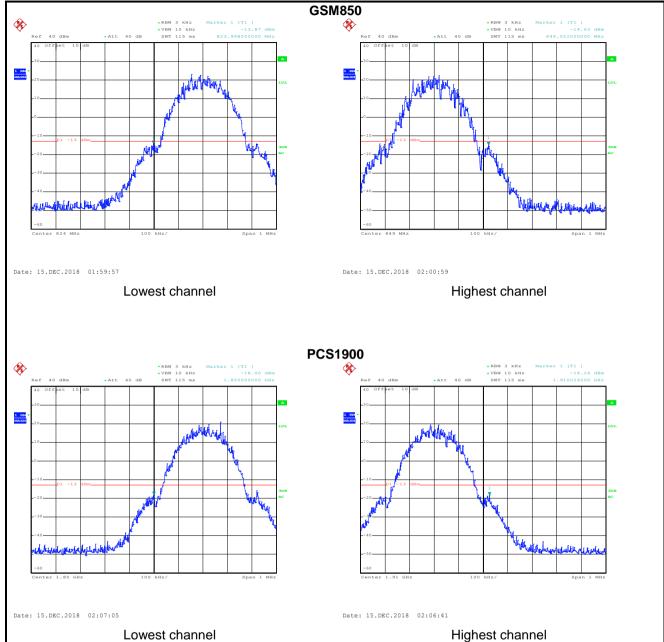




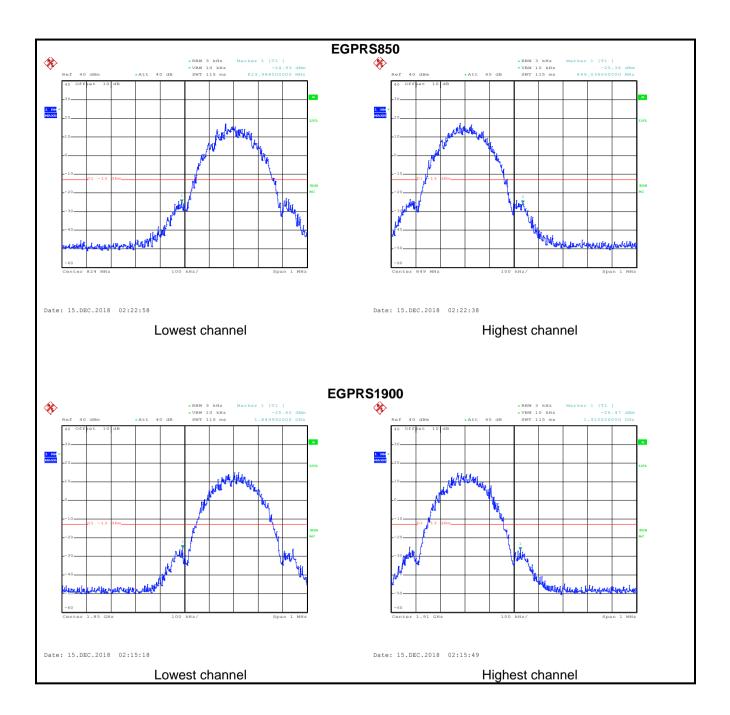




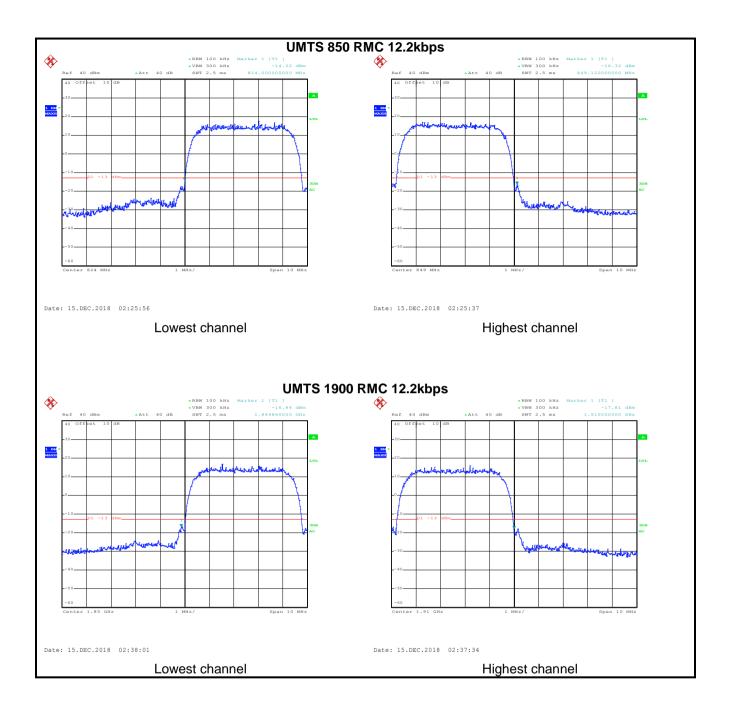




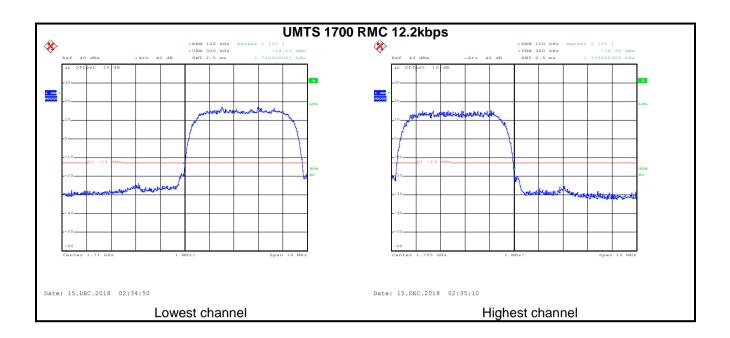














6.6 Field strength of spurious radiation measurement

Test Requirement:	FCC part 22.917(a), FCC part 24.238(a), FCC part 27.53(h)
Test Method:	ANSI/TIA-603-D 2010
Limit:	-13dBm
Limit: Test setup:	Below 1GHz Test Receiver Ham Antenna Tower Ground Reference Plane Test Receiver
Test Procedure:	 The EUT was placed on an non-conductive turntable using a non-conductive support. The radiated emission at the fundamental frequency was measured at 3 m with a test antenna and EMI spectrum analyzer. During the tests, the antenna height and the EUT azimuth were varied in order to identify the maximum level of emissions from the EUT. This maximization process was repeated with the EUT positioned in each of its three orthogonal orientations. The frequency range up to tenth harmonic was investigated for each of three fundamental frequency (low, middle and high channels). Once spurious emission was identified, the power of the emission was determined using the substitution method. The spurious emissions attenuation was calculated as the difference between radiated power at the fundamental frequency and the spurious emissions frequency. ERP / EIRP = S.G. output (dBm) + Antenna Gain(dB/dBi) – Cable Loss (dB)
Test Instruments:	Refer to section 5.8 for details
Test mode:	Refer to section 5.3 for details.
Test results:	Passed





Measurement Data (worst case):

		GSM850			
		Lowest channel			
Fraguenov (MHz)	Spurious	is Emission		Result	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
1648.40	Vertical	-52.31			
2472.60	V	-55.83	-13.00	Pass	
3296.80	V	-54.54			
1648.40	Horizontal	-54.02			
2472.60	Н	-55.35	-13.00	Pass	
3296.80	Н	-54.42			
		Middle channel			
Fraguenov (MUz)	Spurious	Emission	Limit (dPm)	Result	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
1673.20	Vertical	-54.98		Pass	
2509.80	V	-54.34	-13.00		
3346.40	V	-54.01			
1673.20	Horizontal	-54.00			
2509.80	Н	-54.27	-13.00	Pass	
3346.40	Н	-52.97			
		Highest channel			
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result	
Frequency (MHZ)	Polarization	Level (dBm)	Limit (dbm)	Result	
1697.60	Vertical	-55.32			
2546.40	V	-53.64	-13.00	Pass	
3395.20	V	-54.09			
1697.60	Horizontal	-54.66			
2546.40	Н	-53.68	-13.00	Pass	
3395.20	Н	-53.64			

Remark:

^{1.} The emission levels of below 1 GHz are very lower than the limit and not show in test report.





		PCS1900			
		Lowest channel			
Fraguency (MUz)	Spurious Emission		Limit (dPm)	Popult	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
3700.40	Vertical	-52.00	-13.00	Door	
5550.60	V	-45.36	-13.00	Pass	
3700.40	Horizontal	-54.09	42.00	Dana	
5550.60	Н	-44.81	-13.00	Pass	
		Middle channel			
Fragues av (MIII-)	Spurious Emission		Lineit (dDne)	Decult	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
3760.00	Vertical	-41.74	42.00	Poss	
5640.00	V	-41.85	-13.00	Pass	
3760.00	Horizontal	-41.74	42.00	Dana	
5640.00	Н	-41.85	-13.00	Pass	
		Highest channel			
Fragues av (MH=)	Spurious	Emission	Limit (dDm)	Doou!t	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
3819.60	Vertical	-41.79	42.00	Dane	
5729.40	V	-41.94	-13.00	Pass	
3819.60	Horizontal	-52.70	42.00	Door	
5729.40	Н	-46.14	-13.00	Pass	

The emission levels of below 1 GHz are very lower than the limit and not show in test report.



	WCD	MA BAND V 12.2k RN	IC .		
		Lowest channel			
Гио жизо от (МИ I=)	Spurious	Emission	Limit (alDan)	Danilt	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
1652.80	Vertical	-54.50			
2479.20	V	-47.41	-13.00	Pass	
3305.60	V	-53.80			
1652.80	Horizontal	-53.06			
2479.20	Н	-51.56	-13.00	Pass	
3305.60	Н	-53.62	-		
		Middle channel			
Fragues av (MIII-)	Spurious	Emission	Limeit (alDine)	Daguit	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
1673.20	Vertical	-52.16			
2509.80	V	-44.64	-13.00	Pass	
3346.40	V	-54.53			
1673.20	Horizontal	-53.01			
2509.80	Н	-49.36	-13.00	Pass	
3346.40	Н	-54.77			
		Highest channel			
Fragues av (MIII-)	Spurious	Emission	Limeit (alDune)	Daguit	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
1693.20	Vertical	-57.31			
2539.80	V	-44.52	-13.00	Pass	
3386.40	V	-54.44]		
1693.20	Horizontal	-58.79			
2539.80	Н	-46.08	-13.00	Pass	
3386.40	Н	-53.77			

Remark:

^{1.} The emission levels of below 1 GHz are very lower than the limit and not show in test report.



	WCD	MA Band II 12.2k RM	С		
		Lowest channel			
Fraguenov (MIII-)	Spurious	Emission	Limit (dDm)	Dogult	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
3704.80	Vertical	-53.28	-13.00	Pass	
5557.20	V	-48.28	-13.00	Pass	
3704.80	Horizontal	-54.03	-13.00		
5557.20	Н	-49.01	-13.00	Pass	
		Middle channel			
Fragueney (MHz)	Spurious Emission		Limit (dDm)	Result	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
3760.00	Vertical	-52.88	-13.00	Pass	
5640.00	V	-47.90	-13.00	Pass	
3760.00	Horizontal	-54.10	12.00	Door	
5640.00	Н	-47.46	-13.00	Pass	
		Highest channel			
Fraguency (MHz)	Spurious	Emission	Limit (dDm)	Result	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
3815.20	Vertical	-51.37	12.00	Door	
5722.80	V	-47.61	-13.00	Pass	
3815.20	Horizontal	-53.34	12.00	Door	
5722.80	Н	-46.40	-13.00	Pass	

The emission levels of below 1 GHz are very lower than the limit and not show in test report.



	WCD	MA Band IV 12.2k RN	IC		
		Lowest channel			
Fraguenov (MIII-)	Spurious	Emission	Limit (dDm)	Dooult	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
3424.40	Vertical	-52.91	-13.00	Pass	
5136.60	V	-41.65	-13.00	Pass	
3424.40	Horizontal	-52.72	42.00	Dana	
5136.60	Н	-41.67	-13.00	Pass	
·		Middle channel			
Fraguenov (MIII-)	Spurious Emission		Limit (dDm)	Result	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Nesuit	
3464.80	Vertical	-52.25	-13.00	Pass	
5197.20	V	-35.26	-13.00	Pass	
3464.80	Horizontal	-50.30	42.00	Dana	
5197.20	Н	-39.50	-13.00	Pass	
		Highest channel	·		
Fraguency (MIII-)	Spurious	Emission	Limit (dDm)	Dooult	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
3505.20	Vertical	-53.17	12.00	Door	
5257.80	V	-36.47	-13.00	Pass	
3505.20	Horizontal	-53.30	12.00	Door	
5257.80	Н	-39.29	-13.00	Pass	

The emission levels of below 1 GHz are very lower than the limit and not show in test report.



6.7 Frequency stability V.S. Temperature measurement

Test Requirement:	FCC Part 22.355, FCC Part 24.235, FCC Part 27.54, FCC Part 2.1055(a)(1)(b)
Test Method:	ANSI/TIA-6-3-D 2010
Limit:	±2.5 ppm
Test setup:	SS Divider Temperature & Humidity Chamber Power Source
Test procedure:	 The equipment under test was connected to an external DC power supply and input rated voltage. RF output was connected to a frequency counter or spectrum analyzer via feed through attenuators. The EUT was placed inside the temperature chamber. Set the spectrum analyzer RBW low enough to obtain the desired frequency resolution and measure EUT 25°C operating frequency as reference frequency. Turn EUT off and set the chamber temperature to -30°C. After the temperature stabilized for approximately 30 minutes recorded the frequency. Repeat step measure with 10°C increased per stage until the highest temperature of +50°C reached
Test Instruments:	Refer to section 5.8 for details
Test mode:	Refer to section 5.3 for details
Test results:	Passed





Measurement Data (the worst channel):

Refe	erence Frequency: GS	SM850 Middle	channel=190 char	nel=836.6MHz	
Power supplied	Tomporeture (°C)	Frequency error		Limit (none)	Danult
(Vdc)	Temperature (°C)	Hz	ppm	Limit (ppm)	Result
	-30	173	0.206789		
	-20	154	0.184078		
	-10	135	0.161367		
	0	124	0.148219		
3.85	10	113	0.135071	±2.5	Pass
	20	141	0.168539		
	30	138	0.164953		
	40	127	0.151805		
	50	116	0.138656		
Refe	rence Frequency: PC	S1900 Middl	e channel=661 cha	nnel=1880MHz	
Power supplied	Temperature (°C)	Frequency error		Limit (ppm)	Result
(Vdc)	remperature (C)	Hz	ppm	Limit (ppm)	Result
	-30	177	0.09415		
	-20	154	0.08191		
	-10	140	0.07447		
	0	128	0.06809		
3.85	10	124	0.06596	±2.5	Pass
	20	115	0.06117		
	30	106	0.05638		
	40	137	0.07287		
	50	145	0.07713		





Power supplied	T (%C)	Frequency e		1	5
(Vdc)	Temperature (°C)	Hz	ppm	Limit (ppm)	Result
	-30	176	0.210375		
	-20	157	0.187664		
	-10	138	0.164953		
	0	127	0.151805		
3.85	10	116	0.138656	±2.5	Pass
	20	144	0.172125		
	30	141	0.168539		
	40	130	0.155391		
	50	119	0.142242		
Refere	ence Frequency: EGP	RS 1900 Mide	dle channel=661 cl	hannel=1880MHz	
Power supplied	Temperature (°C)	Freq	uency error	Limit (ppm)	Result
(Vdc)	remperature (c)	Hz	ppm	Еппт (ррпп)	Nesuit
	-30	181	0.096277		
	-20	158	0.084043		Pass
	-10	144	0.076596		
	0	132	0.070213		
3.85	10	128	0.068085	±2.5	
	20	119	0.063298		
	30	110	0.058511		
	40	141	0.075000		
	50	149	0.079255	1	





Reference Fred	quency: WCDMA BAN	ND V 12.2k RN	IC Middle channel	=4183 channel=8	36.6MHz
Power supplied	Temperature (°C)	Freq	uency error	Limit (ppm)	Result
(Vdc)	romporatoro (°)	Hz	ppm	Σ (ρρ)	
	-30	168	0.200813		
	-20	141	0.168539		
	-10	134	0.160172		
	0	121	0.144633		
3.85	10	107	0.127899	±2.5	Pass
	20	159	0.190055		
	30	161	0.192446		
	40	137	0.163758		
	50	144	0.172125		
Reference Fre	quency: WCDMA BAI	ND II 12.2k RN	IC Middle channe	=9400 channel=1	880MHz
Power supplied	Tomorosti in 1901	Frequency error		Limit (nnm)	Result
(Vdc)	Temperature (°C)	Hz	ppm	Limit (ppm)	Result
	-30	188	0.10000		
	-20	150	0.07979		
	-10	141	0.07500		
	0	164	0.08723		
3.85	10	143	0.07606	±2.5	Pass
	20	125	0.06649	1	
	30	146	0.07766		
	40	134	0.07128		
	50	150	0.07979		
Reference F	requency: UMTS1700	12.2k RMC N	/liddle channel=14	13 channel=1732	.6MHz
Power supplied	T	Freq	uency error	1	Б. "
(Vdc)	Temperature (°C)	Hz	ppm	Limit (ppm)	Result
	-30	174	0.100427		
	-20	144	0.083112		
	-10	145	0.083689		
	0	128	0.073877		
3.85	10	110	0.063488	±2.5	Pass
	20	146	0.084266	7	
	30	170	0.098118	7	
	40	160	0.092347	7	
	50	131	0.075609	-	



6.8 Frequency stability V.S. Voltage measurement

Test Requirement:	FCC Part 22.355, FCC Part 24.235, FCC Part 27.54, FCC Part 2.1055(d)(2)
Test Method:	ANSI/TIA-603-D 2010
Limit:	±2.5ppm
Test setup:	SS Divider Temperature & Humidity Chamber
Test procedure:	 Set chamber temperature to 25°C. Use a variable DC power source to power the EUT and set the voltage to rated voltage. Set the spectrum analyzer RBW low enough to obtain the desired frequency resolution and recorded the frequency. Reduce the input voltage to specify extreme voltage variation (+/-15%) and endpoint, record the maximum frequency change.
Test Instruments:	Refer to section 5.8 for details
Test mode:	Refer to section 5.3 for details
Test results:	Passed





Measurement Data (the worst channel):

Refer	ence Frequency: G	SM850 Middle	channel=190 chan	nel=836.6MHz	
	Power supplied		uency error		
Temperature (°C)	(Vdc)	Hz	ppm	Limit (ppm)	Result
	4.40	84	0.100406		
25	3.85	77	0.092039	±2.5	Pass
20	3.50	67	0.080086	-	1 400
Refer	ence Frequency: PC			 nnel=1880MHz	
- Itoloi					
Temperature (°C)	Power supplied (Vdc)	Hz	ppm	Limit (ppm)	Result
	4.40	88	0.04681		
25	3.85	72	0.03830	_ ±2.5	Pass
23	3.50	78	0.03330		rass
Doforos	nce Frequency: EGF				
Referei	1				
Temperature (℃)	Power supplied (Vdc)		iency error	Limit (ppm)	Result
	` ,	Hz	ppm		
	4.40	98	0.117141		
25	3.85	90	0.107578	±2.5	Pass
	3.50	72	0.086063		
Referer	nce Frequency: EGP	RS 1900 Midd	le channel= 661 ch	nannel=1880MHz	
Tomporatura (°C)	Power supplied	Frequency error		Limit (name)	Dogult
Temperature (°C)	(Vdc)	Hz	ppm	Limit (ppm)	Result
	4.40	87	0.046277		
25	3.85	76	0.040426	±2.5	Pass
	3.50	88	0.046809	1	
Note: Only the worst cas	se shown in the report.	<u>'</u>	<u>'</u>	· '	





Reference	Frequency: UMTS 8	50 12.2k RMC M	iddle channel=41	83 channel=836.6	6MHz
Temperature (°C)	Power supplied	Freque	Frequency error		D !!
	(Vdc)	Hz	ppm	Limit (ppm)	Result
	4.40	86	0.102797		
25	3.85	92	0.109969	±2.5	Pass
	3.50	65	0.077695		
Reference I	requency: UMTS 19	000 12.2k RMC I	/liddle channel=9	400 channel=1886	OMHz
Tamparatura (°C)	Power supplied	Frequency error		Limit (none)	Danult
Temperature (°C)	(Vdc)	Hz	ppm	Limit (ppm)	Result
	4.40	80	0.042553		Pass
25	3.85	83	0.044149	±2.5	
	3.50	71	0.037766		
Reference F	requency: UMTS170	00 12.2k RMC M	iddle channel=14	13 channel=1732.	6MHz
Tomporature (°C)	Power supplied	Frequency error		L'ar't (a.e.a)	
Temperature (°C)	(Vdc)	Hz	ppm	Limit (ppm)	Result
	4.40	92	0.053099		
25	3.85	86	0.049636	2.5	Pass
	3.50	59	0.034053	1	1